

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination PAN ET AL.	
		Examiner Seth Barnes	Art Unit 2822	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0087503 A1	05-2003	Sakaguchi et al.	438/406
*	B	US-5,028,558	07-1991	Haisma et al.	438/3
*	C	US-4,142,925	03-1979	King et al.	438/60
*	D	US-6,498,073 B2	12-2002	Sarma et al.	438/459
*	E	US-2004/0067621 A1	04-2004	Yanagita et al.	438/455
*	F	US-5,536,361	07-1996	Kondo et al.	438/492
*	G	US-2005/0074954 A1	04-2005	Yamanaka, Hideo	438/458
*	H	US-2006/0006488 A1	01-2006	Kanbe, Hideo	257/443
*	I	US-6,607,968 B1	08-2003	Jurczak et al.	438/455
*	J	US-2005/0205930 A1	09-2005	Williams, George Melville JR.	257/347
*	K	US-2004/0014240 A1	01-2004	Takeguchi et al.	436/518
*	L	US-2005/0110159 A1	05-2005	Oh et al.	257/777
*	M	US-2004/0262635 A1	12-2004	Lee, Sang-Yun	257/199

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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